

Contents

<i>Editor's preface</i>	V
<i>Author's preface</i>	VII
<i>Acknowledgements</i>	XI
<i>Chapter 1. Introduction</i>	I
<i>Chapter 2. Factors to be considered in image interpretation</i>	7
2.1 Specimen staining	8
2.2 Radiation damage	11
2.3 Specimen thickness	16
2.4 Objective lens defocus and lens aberrations	18
2.5 Contrast and resolution	21
2.5.1 Contrast mechanisms	23
2.5.2 Elastic and inelastic scattering	25
<i>Chapter 3. Image analysis</i>	33
3.1 The Fourier transform	34
3.1.1 Detection of image defects and amount of defocus	36
3.1.2 Analysis of a regular array of subunits	37
3.1.3 Separation of information from overlapping layers	39
3.1.4 Analysis of helices	39
3.1.5 Analysis of particles with rotational symmetry	40
3.2 Theory of image formation for a thin specimen	40
3.2.1 Specimen thickness limitation in the weak phase approximation	46
3.2.2 The transfer function of the electron microscope	48
3.3 Optical analysis of images	53
3.3.1 The optical transform and optical diffractometry	56
3.3.2 Assessment of images: image quality	59

3.3.3	Assessment of images: image resolution	66
3.3.4	Measurement of defocus from optical transforms	75
3.4	Computer analysis of images	78
3.4.1	Densitometry and digitising micrographs	78
3.4.2	The fast Fourier transform (FFT)	80
3.4.3	The analysis of numerical transforms: amplitude and phase information	86
3.5	Optical versus computer analysis of electron micrographs	91
3.6	Diffraction by helices	95
3.6.1	The diffraction pattern of a continuous helix	97
3.6.2	The diffraction pattern of a discontinuous helix	98
3.6.3	The calculation of the numerical transform of a helical particle	102
3.6.4	The separation of the helical diffraction pattern into two components	104
3.7	Indexing diffraction patterns	106
3.7.1	Simple lattices	107
3.7.2	Superimposed lattices	114
3.7.3	Helical particles	119

Chapter 4. Image processing 125

4.1	Specimens with rotational symmetry	129
4.1.1	Photographic superposition	129
4.1.2	Computer methods: analysis	130
4.1.3	Computer methods: applications	137
4.1.4	Photographic versus computer methods	138
4.2	Specimens with translational symmetry	139
4.2.1	Photographic superposition	140
4.2.2	Computer and optical methods: analysis	142
4.2.3	Computer methods: refinements and results	147
4.2.4	A comparison of computer and optical filtering	160
4.3	Separating superimposed lattices	162
4.4	Correction of images for defocus and lens defects	169
4.5	The use of electron diffraction data in image processing	171
4.6	Computer processing of images of thick specimens	176
4.6.1	The weak phase-weak amplitude approximation	176
4.7	Averaging and spatial filtering for non-periodic specimens	181
4.7.1	Photographic superposition	182
4.7.2	Computer superposition	186
4.7.3	Spatial filtering using the Fourier transform of the image	190

Chapter 5. Instrumental methods of contrast enhancement 199

5.1	Increasing the focal length of the objective lens	202
5.2	Applications of the energy-selecting electron microscope	208
5.3	Scanning transmission electron microscopy (STEM)	209
5.3.1	Theory of image formation in the STEM	211
5.3.2	Applications of STEM	214
5.3.3	Separation of inelastic and elastic components	217
5.4	Dark-field electron microscopy	219
5.4.1	Dark-field versus bright-field microscopy	220

5.4.2	Different types of dark-field microscopy	224
5.4.3	Application of dark-field microscopy to sectioned material	226
5.4.4	Application of dark-field microscopy to unstained specimens	228
5.4.5	Atomic and molecular resolution	229
5.5	Coherent versus incoherent electron illumination	232
5.6	Optical shadowing or topographical imaging	235
5.6.1	Theory of optical shadowing for thin specimens	236
5.7	<i>In situ</i> double exposures for enhancing phase contrast	238

Chapter 6. Computer methods of contrast enhancement 245

6.1	Subtraction of background	247
6.2	Image subtraction	249
6.2.1	Theory of image subtraction	249
6.2.2	Practical problems in image subtraction	251
6.2.3	Applications of image subtraction	252
6.3	Enhancement of boundary structure	254
6.3.1	The density histogram and thresholding	254
6.3.2	The use of the Laplacian for enhancing boundary structure	256

Chapter 7. Image interpretation 259

7.1	Effects of specimen staining	259
7.2	Radiation damage	265
7.3	The effect of specimen thickness	269
7.3.1	High resolution electron microscopy	270
7.3.2	Phase contrast versus scattering contrast	272
7.3.3	Resolution limitations	273
7.4	Limitations of two-dimensional information	276
7.4.1	Three-dimensional reconstruction: principles	278
7.4.2	Three-dimensional reconstruction: crystalline specimens	281
7.4.3	Three-dimensional reconstruction: helical particles	282
7.4.4	Three-dimensional reconstruction: asymmetric particles	286

Appendix. List of suppliers 293

Subject index 297